A B S T R A C T

A defect detecting apparatus of the present invention includes an object to be inspected, an illuminating light source unit inclined at a predetermined angle to the object to irradiate the object with illuminating light, an image sensing unit inclined at a predetermined angle to the object to sense an image of diffracted light from the object, an angle controller which changes the inclination angle of at least one of the illuminating unit and the image sensing unit, an image processor which receives the diffracted light from the object by using the image sensing unit at each inclination angle, and obtaining the luminance value of the diffracted light at inclination angle, a determination unit which determines the nth-order light best suited to observation with respect to the diffracted light from the relationship between the inclination angle and the luminance value, and an angle controller which sets the inclination angle of at least one of the illuminating unit and the image sensing unit on the basis of the determination result.

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